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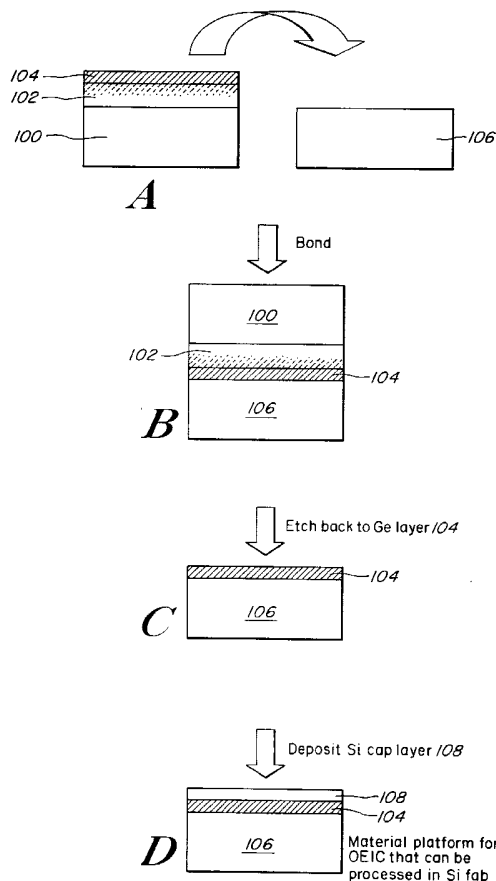
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[Continued on next page]

(54) Title: SILICON WAFER WITH EMBEDDED OPTOELECTRONIC MATERIAL FOR MONOLITHIC OEIC



(57) Abstract: A structure with an optically active layer embedded in a Si wafer, such that the outermost epitaxial layer exposed to the CMOS processing equipment is always Si or another CMOS-compatible material such as SiO₂. Since the optoelectronic layer is completely surrounded by Si, the wafer is fully compatible with standard Si CMOS manufacturing. For wavelengths of light longer than the bandgap of Si (1.1 μm), Si is completely transparent and therefore optical signals can be transmitted between the embedded optoelectronic layer and an external waveguide using either normal incidence (through the Si substrate or top Si cap layer) or in-plane incidence (edge coupling).



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INTERNATIONAL SEARCH REPORT

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A. CLASSIFICATION OF SUBJECT MATTER

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According to International Patent Classification (IPC) or to both national classification and IPC

B. FIELDS SEARCHED

Minimum documentation searched (classification system followed by classification symbols)

IPC 7 H01L

Documentation searched other than minimum documentation to the extent that such documents are included in the fields searched

Electronic data base consulted during the international search (name of data base and, where practical, search terms used)

EPO-Internal, PAJ, INSPEC

C. DOCUMENTS CONSIDERED TO BE RELEVANT

Category °	Citation of document, with indication, where appropriate, of the relevant passages	Relevant to claim No.
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A	page 4, line 17-25 page 12, line 1-18; figure 4	1, 17, 25
A	PATENT ABSTRACTS OF JAPAN vol. 015, no. 098 (E-1042), 8 March 1991 (1991-03-08) & JP 02 306680 A (HIKARI GIJUTSU KENKYU KAIHATSU KK), 20 December 1990 (1990-12-20) abstract	1, 17, 25, 41
A	WO 98 59365 A (MASSACHUSETTS INST TECHNOLOGY) 30 December 1998 (1998-12-30) cited in the application the whole document	1-58
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Further documents are listed in the continuation of box C.



Patent family members are listed in annex.

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C.(Continuation) DOCUMENTS CONSIDERED TO BE RELEVANT

Category °	Citation of document, with indication, where appropriate, of the relevant passages	Relevant to claim No.
A	<p>WADA H ET AL: "ROOM-TEMPERATURE PHOTO-PUMPED OPERATION OF 1.58-MUM VERTICAL-CAVITY LASERS FABRICATED ON SI SUBSTRATES USING WAFER BONDING" IEEE PHOTONICS TECHNOLOGY LETTERS, IEEE INC. NEW YORK, US, vol. 8, no. 11, 1 November 1996 (1996-11-01), pages 1426-1428, XP000632619 ISSN: 1041-1135 figure 1</p>	1, 17, 25, 41
A	<p>MATSUO S ET AL: "Use of polyimide bonding for hybrid integration of a vertical cavity surface emitting laser on a silicon substrate" ELECTRONICS LETTERS, IEE STEVENAGE, GB, vol. 33, no. 13, 19 June 1997 (1997-06-19), pages 1148-1149, XP006007611 ISSN: 0013-5194 figures 1,2</p>	1, 17, 25, 41
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A	<p>US 5 937 274 A (UOMI KAZUHISA ET AL) 10 August 1999 (1999-08-10) the whole document</p>	1, 17, 25, 41

INTERNATIONAL SEARCH REPORT

Information on patent family members

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